## Notice of References Cited Application/Control No. 10/593,297 Examiner Harry Liu Applicant(s)/Patent Under Reexamination HAN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,501,955 B1	12-2002	Durrant et al.	455/456.1
*	В	US-2003/0008669 A1	01-2003	Stein et al.	455/456
*	С	US-2003/0054813 A1	03-2003	Riley et al.	455/424
*	D	US-2003/0125045 A1	07-2003	Riley et al.	455/456
*	Ε	US-6,665,539 B2	12-2003	Sih et al.	455/456.3
*	F	US-2004/0121774 A1	06-2004	Rajkotia et al.	455/441
*	G	US-2004/0165657 A1	08-2004	Simic et al.	375/211
*	Н	US-2004/0219930 A1	11-2004	Lin, le-Hong	455/456.1
*	1	US-7,039,418 B2	05-2006	Amerga et al.	455/456.1
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P			<u> </u>		
	Q					
	R				·	
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>v</b>	
	w	
	x	(C MDED 5 707 05(a) )

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.